



SPECIFICATION

PN: SJK-6MH25175M5Z0430A6

深圳市晶科鑫实业有限公司

SHENZHEN CRYSTAL TECHNOLOGY INDUSTRIAL CO., LTD.

VER	DESIGNED	CHECKED	APPROVED
A1	何丹斌	李相同	刘忠亮

CUSTOMER APPROVAL

SPECIFICATION :		晶振 / Half Size / 25.175MHz	
SJK PN. :		SJK-6MH25175M5Z0430A6	
CUSTOMER PN. :			
CHECKED 1	CHECKED 2	APPROVED	DATE
Result: <input type="checkbox"/> PASS <input type="checkbox"/> FAIL <input type="checkbox"/> OTHER			

FEATURE

- Small Size as small as 12.8x 12.8x 5.0mm.
- Hybrid IC Circuit Construction.
- CMOS compatible output.
- 5V and 3.3V supply model available.
- All metal, hermetically sealed welded package.
- High precision characteristic covering to high frequency range.
- RoHS and Pb Free compliant.

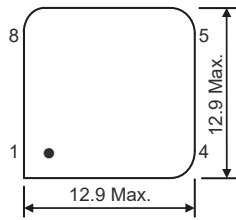
ELECTRICAL SPECIFICATIONS

Model Type		Half Size
Fan Out Type		CMOS
Supply Range		5.0V ±10%DC
Frequency Range		25.175MHz
Operating Temperature		-40~85°C
Frequency Range Input Current		10mA Max
Rise time(Tr) and Fall time(Tf)		5ns Max
Frequency Stability	All Conditions	±30ppm
Symmetry	AT 1/2 Vdd	45/55%
Output level	"0"level(Vol)	10%VccMax
	"1"level(Voh)	90%VccMin
Output load	CMOS	15PF
Storage temperature		-55~125°C

Crystal Oscillator CMOS Output Half Size 6MH Series

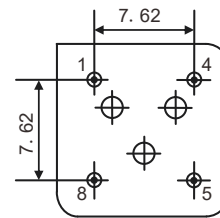
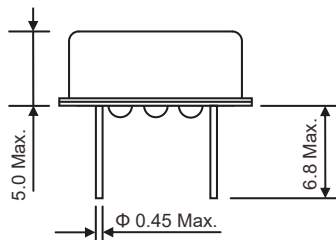


DIMENSION (Unit: mm)



Pin Connections

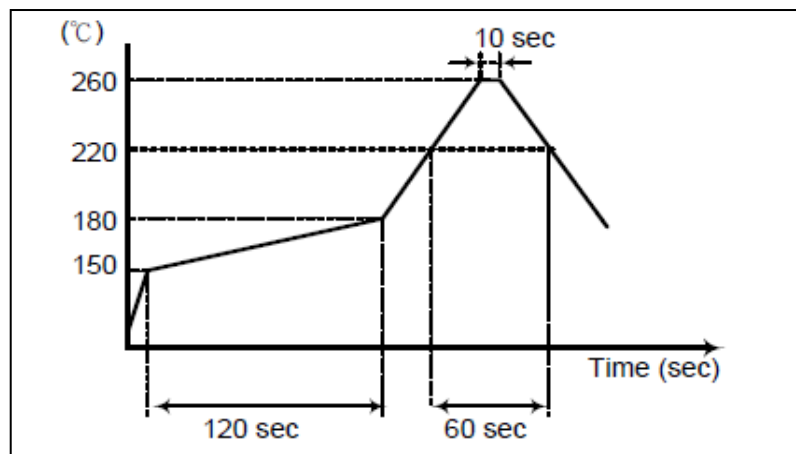
Pin No.	Connection
1	NC (Not connect)
4	GND
5	Output
8	Vdd



MARK

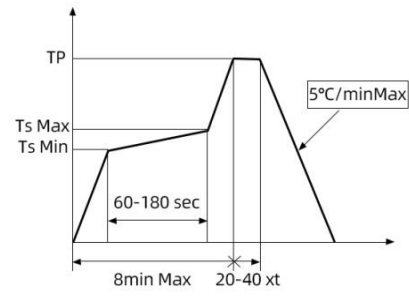


REFLOW CONDITION



The reflow temperature profile may vary depending on the product model, specifications and frequency range. Refer to the individual product specifications for details

RELIABILITY TEST SPECIFICATIONS

Test item	Equipment	Condition	Specification
1.SOLDERABILITY TEST	SJK-REL001、RC-328A	TP:260℃ TsMax: 200℃ TsMin: 150℃ 2 time 	MIL-STD-883E Method 2003.7
2. HERMETICITY TEST	HELIOT-306S	Pressurized 0.4~0.5Mpa ethanol sealed tank for 10 minutes	MIL-STD-883E Method 1014.10
3. VIBRATION TEST	HG-V4、S&A 250B	Enable Crystal(10g) from 10-55-10Hz,X、Y、Z horizontal,1 Minute vibration/time, 1time/ 2 hours.	MIL-STD-883E Method 2007.3
4. MECHANICAL SHOCK	HPC-200、S&A 250B	Enable Crystal 50G(490m/s ²) time=11 ms speed=3.4 m/s half sine wave oscillation	JIS C6701
5. DROP TEST	HARD BOARD.S&A250B	75cm High,3 times on hard board	MIL-STD-202F Method 213B
6. HIGH&LOW TEMP STORAGE TEST(Static test)	H-PTH-80CK & HM101-3ABN, S&A 350B/250B	High temperature: 125℃±2℃,1000hr; Low temperature:-40℃±3℃,1000hrs	MIL-STD883C, METHOD 1011.8
7. TEMP & HUM CYCLING TEST	H-PTH-80CK CHAMBE, S&A 350B/250B	Temperature:-10℃±2℃~65℃±2℃,Humidity:93±3%,1 cycle need 24 hrs. 5cycles.	MIL-STD-883E Method 1005.8
8. HIGH TEM. & HUM.STORAGE TEST	H-PTH-80CK CHAMBE, S&A350B/250B	Temperature:85℃±2, Humidity:85+3,-2%,Store 96 hrs	JIS C6701
9. AGING TEST	H-PTH-80CK CHAMBE, S&A350B/250	Temperature:85℃±2, Store 1000 hrs	JIS C5023

REVISION RECORD (SJK-6MH25175M5Z0430A6)

Rev	Revise contents	Reason	Reviser	Checked	Approved
A1	Initial released	--	贺丹斌	李相同	刘惠光